

<b>Notice of References Cited</b>	Application/Control No. 10/817,417		Applicant(s)/Patent Under Reexamination YUE ET AL	
	Examiner Kin-Chan Chen		Art Unit 1765	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,884,734	04-2005	Buehrer et al.	438/723
*	B	US-6,926,843	08-2005	Cantell et al.	216/51
*	C	US-2004/0191998	09-2004	Natzle et al.	438/300
*	D	US-2005/0218113	10-2005	Yue, Hongyu	216/059
*	E	US-2005/0227494	10-2005	Higuchi et al.	438/706
*	F	US-2004/0097047	05-2004	Natzle et al.	438/300
*	G	US-2004/0185583	09-2004	Tomoyasu et al.	438/008
*	H	US-2004/0241981	12-2004	Doris et al.	438/637
*	I	US-2004/0110354	06-2004	Natzle et al.	438/365
*	J	US-5,282,925	02-1994	Jeng et al.	216/59
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.